



RF Exposure TEST REPORT

FCC Per 47 CFR 2.1091(b)

FCC ID..... : YVV-PD20

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Date of issue.....: Apr 22, 2011

Testing Laboratory Name.....: Shenzhen Huatongwei International Inspection Co., Ltd

Address.....: Keji Nan No.12 Road, Hi-tech Park, Shenzhen, China

Applicant's name.....: Shenzhen AEE Technology Co.,Ltd.

Address.....: AEE Hi-Tech Park, Sun Industrial Area, Xili, Nanshan District, Shenzhen, P.R.C

Test specification:

Standard.....: FCC Part 15.247: Operation within the bands 920-928 MHz, 2400-2483.5 MHz and 5725-5850 MHz Direct Sequence System

TRF Originator.....: Shenzhen Huatongwei International Inspection CO., Ltd

Master TRF.....: Dated 2006-06

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Test item description.....: Hands Free Camcorder

Trade Mark.....: /

Model/Type reference.....: PD20

Listed Models.....: ED20

Result.....: Positive

RF Exposure T E S T R E P O R T

FCC ID :	YVV-PD20	Apr 22, 2011
		Date of issue

Equipment under Test : Hands Free Camcorder

Model /Type : PD20

Listed Models : ED20

Applicant : **Shenzhen AEE Technology Co.,Ltd.**

Address : AEE Hi-Tech Park,Sun Industrial Area,Xili,Nanshan District,Shenzhen,P.R.C

Manufacturer : **Shenzhen AEE Technology Co.,Ltd.**

Address : AEE Hi-Tech Park,Sun Industrial Area,Xili,Nanshan District,Shenzhen,P.R.C

The test report merely corresponds to the test sample.

It is not permitted to copy extracts of these test result without the written permission of the test laboratory.

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Modulation Mode	TX Function
Bluetooth	1TX

2. TEST ENVIRONMENT

2.1. Address of the test laboratory

Shenzhen Huatongwei International Inspection Co., Ltd
Keji Nan No.12 Road, Hi-tech Park, Shenzhen, China
Phone: 86-755-26715686 Fax: 86-755-26748089

The sites are constructed in conformance with the requirements of ANSI C63.7, ANSI C63.4 (2009) and CISPR Publication 22.

2.2. Environmental conditions

During the measurement the environmental conditions were within the listed ranges:

Temperature:	<u>15-35 ° C</u>
Humidity:	<u>30-60 %</u>
Atmospheric pressure:	<u>950-1050mbar</u>

2.3. Statement of the measurement uncertainty

The data and results referenced in this document are true and accurate. The reader is cautioned that there may be errors within the calibration limits of the equipment and facilities. The measurement uncertainty was calculated for all measurements listed in this test report acc. to CISPR 16 - 4 „Specification for radio disturbance and immunity measuring apparatus and methods – Part 4: Uncertainty in EMC Measurements“ and is documented in the Shenzhen Huatongwei International Inspection Co., Ltd quality system acc. to DIN EN ISO/IEC 17025. Furthermore, component and process variability of devices similar to that tested may result in additional deviation. The manufacturer has the sole responsibility of continued compliance of the device.

Hereafter the best measurement capability for Shenzhen Huatongwei laboratory is reported:

Test	Range	Measurement Uncertainty	Notes
Radiated Emission	30~1000MHz	4.24 dB	(1)
Radiated Emission	1~18GHz	5.16 dB	(1)
Radiated Emission	18-40GHz	5.54 dB	(1)
Conducted Disturbance	0.15~30MHz	3.39 dB	(1)

(1) This uncertainty represents an expanded uncertainty expressed at approximately the 95% confidence level using a coverage factor of k=2.

3. Method of measurement

3.1. Applicable Standard

According to §1.1307(b)(1), systems operating under the provisions of this section shall be operated in a manner that ensures that the public is not exposed to radio frequency energy level in excess of the Commission's guidelines.

According to §1.1310 and §2.1091 RF exposure is calculated.

3.2. Limit

Exposure category	<u>low threshold</u>	<u>high threshold</u>
general population	$(60/f_{\text{GHz}}) \text{ mW}, d < 2.5 \text{ cm}$ $(120/f_{\text{GHz}}) \text{ mW}, d \geq 2.5 \text{ cm}$	$(900/f_{\text{GHz}}) \text{ mW}, d < 20 \text{ cm}$
occupational	$(375/f_{\text{GHz}}) \text{ mW}, d < 2.5 \text{ cm}$ $(900/f_{\text{GHz}}) \text{ mW}, d \geq 2.5 \text{ cm}$	$(2250/f_{\text{GHz}}) \text{ mW}, d < 20 \text{ cm}$

F=frequency in GHz

3.3. RF Exposure

TEST RESULTS

The max peak output power is 3.245dBm . The antenna gain is 0.58dBi. EIRP=3.825dBm=2.41mW< 60/2.48=24mW, so the SAR is not required.

4. Conclusion

The measurement results comply with the FCC Limit per 47 CFR 2.1091 for the controlled RF Exposure.

.....**End of Report**.....